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Application/Control No.	Applicant(s)/Patent under Reexamination
10/079,468	FENDER ET AL.
Examiner	Art Unit
Dakia Mikalawa	1004

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INTERFERENCE SEARCHED					
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SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
Google Scholar: NIR spectroscopy, soybean	4/25/2007	PW
EAST: see attached	4/25/2007	PW
Inventor search: palm	4/25/2007	PW
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